Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/602,804	MCILWAINE ET AL.	
Examiner	Art Unit	
Quynh H. Nguyen	2614	

SEARCHED					
OLAKONED					
Class	Subclass	Date	Examiner		
379	265.01 265.02 265.05 266.07	6/7/06	QN		
above	updated	11/15/2006	QN		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Searched: East, USPGPub, USPAT	6/7/06	QN	
Inventor searched through PALM database	6/7/06	QN	